



Product Change Notification - GBNG-31NTMF621

Date:

13 Sep 2018

Product Category:

Interface- LIN Transceiver; Interface- Controller Area Network (CAN)

Affected CPNs:**Notification subject:**

CCB 3533 Initial Notice: Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN and 16L VDFN packages.

Notification text:**PCN Status:**

Initial notification.

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN and 16L VDFN packages.

Pre Change:

Tested at MPHL final test site.

Post Change:

Tested at MPHL final test site or tested at MTAI final test site.

Pre and Post Change Summary:

	Pre Change	Post Change	
Final Test Site	Microchip Technology Operations (Philippines) Corporation (MPHL)	Microchip Technology Operations (Philippines) Corporation (MPHL)	Microchip Technology Thailand (HQ) (MTAI)

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve manufacturability by qualifying MTAI as an additional final test site.

Change Implementation Status:

In Progress

Estimated Qualification Completion Date:

October 2018

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may



receive pre and post change parts.

Time Table Summary:

	September 2018				-->	October 2018			
Workweek	36	37	38	39		40	41	42	43
Initial PCN Issue Date		X							
Qual Report Availability						X			
Final PCN Issue Date						X			

Method to Identify Change:

Traceability code

Qualification Plan:

Please open the attachments included with this PCN labeled as PCN_#_Qual Plan.

Revision History:

September 13, 2018: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

[PCN_GBNG-31NTMF621_Qual Plan.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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MICROCHIP

QUALIFICATION PLAN SUMMARY

PCN #: GBNG-31NTMF621

Date
August 24, 2018

Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN and 16L VDFN packages.

Purpose: Qualification of MTAI as an additional final test site for selected Atmel automotive products available in 8L SOIC, 14L SOIC, 8L VDFN, 14L VDFN and 16L VDFN packages.

CCB No.: 3533

Test / Evaluation	Test Conditions / Parameters
Datalog / Bin Comparison	<ul style="list-style-type: none"> • Compare test numbers, test names, test limit, test sequence, bin assignments & pass/fail results • Accept if all match or justify the differences
Test stability verification	<ul style="list-style-type: none"> • 50 loops on single TD (60 Sites) with STDF • Accept on Cp > 1.67 or justify/waive parameters if needed
Parametric Correlation	<ul style="list-style-type: none"> • Perform GR&R. Site 1: SPEA vs LTX • Accept on GR&R < 10% or justify/waive parameters if needed
Site to site comparison	<ul style="list-style-type: none"> • Perform test capability and compare (TCC). SPEA_Site1 vs SPEA_SiteX. • Accept R&R < 10% and Cpk >1.67 or justify/waive parameters if needed
Unit to unit parametric correlation	<ul style="list-style-type: none"> • Run one full strip or >50 units correlation on strip, serialize, then run in singulated. • Accept if all match or justify the differences (including reject correlation)
Peak Voltage	<ul style="list-style-type: none"> • Check voltage peaks for each device pin at SPEA (minimum of 2 sites). • No voltage peaks > Maximum Ratings from datasheet.
Lot Correlation	<p><u>3 Lots Correlation /~5k per lot</u></p> <ul style="list-style-type: none"> • 100% test on Strip with SPEA tester, send back to assembly for singulation, then 100% test on singulated tester. • Accept $\pm 0.1\%$ yield difference, Sigma Ratio <1.5 and Delta Average <10%. Reject should be matched or justify the differences.

Affected Catalog Part Numbers (CPN)

ATA663354-GDQW
ATA663331-GDQW
ATA663454-GDQW
ATA663431-GDQW
ATA6562-GAQW0
ATA6566-GAQW0
ATA6563-GAQW0
ATA6564-GAQW0
ATA6562-GBQW0
ATA6566-GBQW0
ATA6563-GBQW0
ATA6564-GBQW0
ATA6565-GCQW0
ATA6562-GAQW1
ATA6561-GAQW
ATA6560-GAQW
ATA6564-GAQW1
ATA6563-GAQW1
ATA6566-GAQW1
ATA6560-GAQW-N
ATA6561-GAQW-N
ATA6562-GBQW1
ATA6561-GBQW
ATA6560-GBQW
ATA6564-GBQW1
ATA6563-GBQW1
ATA6566-GBQW1
ATA6560-GBQW-N
ATA6561-GBQW-N
ATA6565-GCQW1
ATA6570-GNQW1